

<b>Search Notes</b>  <b>*1054980</b>  <b>1*</b>	<b>Application/Control No.</b>  10549801	<b>Applicant(s)/Patent Under Reexamination</b>  FUNAHASHI, MASAKAZU
	<b>Examiner</b>  Dawn Garrett	<b>Art Unit</b>  1786

SEARCHED			
Class	Subclass	Date	Examiner
428	690, 917 (see EAST search printout for all listed - limited by keywords)	7-27-08	DG
313	504, 506	7-27-08	DG
257	E51.05, E51.051	7-27-08	DG
564	426, 434	7-27-08	DG
	see EAST search history	12/2010	DG

SEARCH NOTES		
Search Notes	Date	Examiner
EIC 1700 STIC structure search - see printout	7-22-08	DG
Inventor Name Search	7-27-08	DG
EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	7-27-08	DG
updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	4-2-2009 and 4-4-2009	DG
updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	8-19-2009 and 8-22-2009	DG
updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	5-12-2010	DG
updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	12-16-2010	DG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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